


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/708,371	CHAN ET AL.	
	Examiner	Art Unit	
	Linh V. Nguyen	2819	

SEARCHED			
Class	Subclass	Date	Examiner
330	285,261 196	6/9/2005	LN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
330	136	6/9/2005	LN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
high, power, amplifier, bias, input ,gate, diode, resistior	6/9/2005	LN